

# IMPORTANT NOTICE

10 December 2015

## 1. Global joint venture starts operations as WeEn Semiconductors

Dear customer,

As from November 9th, 2015 NXP Semiconductors N.V. and Beijing JianGuang Asset Management Co. Ltd established Bipolar Power joint venture (JV), **WeEn Semiconductors**, which will be used in future Bipolar Power documents together with new contact details.

In this document where the previous NXP references remain, please use the new links as shown below.

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Thank you for your cooperation and understanding,

WeEn Semiconductors



# BTA330Y-800BT

3Q Hi-Com Triac

27 July 2015

Product data sheet

## 1. General description

Planar passivated high commutation three quadrant triac in a SOT78D (TO-220AB) internally insulated plastic package intended for use in circuits where high static and dynamic  $dV/dt$  and high  $di/dt$  can occur. This triac will commutate the full RMS current at the maximum rated junction temperature ( $T_{j(max)} = 150^\circ\text{C}$ ) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

## 2. Features and benefits

- 3Q technology for improved noise immunity
- High commutation capability with maximum false trigger immunity
- High junction operating temperature capability ( $T_{j(max)} = 150^\circ\text{C}$ )
- High voltage capability
- High current capability
- Less sensitive gate for highest noise immunity
- Internally insulated package
- Internally isolated mounting base
- Triggering in three quadrants only
- Very high immunity to false turn-on by  $dv/dt$  and IEC 61000-4-4 fast transient
- Package is RoHS compliant
- Package meets UL94V0 flammability requirement
- Package meets UL1557 isolation test requirement rated at 2500V RMS

## 3. Applications

- Heating controls
- High power motor control
- High power switching
- Applications subject to high temperature ( $T_{j(max)} = 150^\circ\text{C}$ )

## 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	-	800	V
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_{mb} \leq 86^\circ\text{C}$ ; <a href="#">Fig. 1</a> ; <a href="#">Fig. 2</a> ; <a href="#">Fig. 3</a>	-	-	30	A

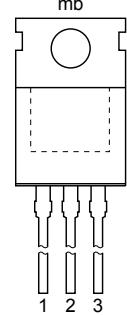
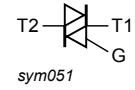


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Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$I_{TSM}$	non-repetitive peak on-state current	full sine wave; $T_{j(\text{init})} = 25^\circ\text{C}$ ; $t_p = 20 \text{ ms}$ ; <a href="#">Fig. 4</a> ; <a href="#">Fig. 5</a>		-	-	270	A
		full sine wave; $T_{j(\text{init})} = 25^\circ\text{C}$ ; $t_p = 16.7 \text{ ms}$		-	-	297	A
$T_j$	junction temperature			-	-	150	°C
<b>Static characteristics</b>							
$I_{GT}$	gate trigger current	$V_D = 12 \text{ V}$ ; $I_T = 0.1 \text{ A}$ ; T2+ G+; $T_j = 25^\circ\text{C}$ ; <a href="#">Fig. 7</a>		-	-	50	mA
		$V_D = 12 \text{ V}$ ; $I_T = 0.1 \text{ A}$ ; T2+ G-; $T_j = 25^\circ\text{C}$ ; <a href="#">Fig. 7</a>		-	-	50	mA
		$V_D = 12 \text{ V}$ ; $I_T = 0.1 \text{ A}$ ; T2- G-; $T_j = 25^\circ\text{C}$ ; <a href="#">Fig. 7</a>		-	-	50	mA
$I_H$	holding current	$V_D = 12 \text{ V}$ ; $T_j = 25^\circ\text{C}$ ; <a href="#">Fig. 9</a>		-	-	75	mA
$V_T$	on-state voltage	$I_T = 42 \text{ A}$ ; $T_j = 25^\circ\text{C}$ ; <a href="#">Fig. 10</a>		-	1.2	1.55	V
<b>Dynamic characteristics</b>							
$dV_D/dt$	rate of rise of off-state voltage	$V_{DM} = 536 \text{ V}$ ; $T_j = 125^\circ\text{C}$ ; ( $V_{DM} = 67\%$ of $V_{DRM}$ ); exponential waveform; gate open circuit		4000	-	-	V/μs
		$V_{DM} = 536 \text{ V}$ ; $T_j = 150^\circ\text{C}$ ; ( $V_{DM} = 67\%$ of $V_{DRM}$ ); exponential waveform; gate open circuit		2000	-	-	V/μs
$dI_{com}/dt$	rate of change of commutating current	$V_D = 400 \text{ V}$ ; $T_j = 125^\circ\text{C}$ ; $I_{T(\text{RMS})} = 30 \text{ A}$ ; $dV_{com}/dt = 20 \text{ V}/\mu\text{s}$ ; (snubberless condition); gate open circuit		20	-	-	A/ms
		$V_D = 400 \text{ V}$ ; $T_j = 150^\circ\text{C}$ ; $I_{T(\text{RMS})} = 30 \text{ A}$ ; $dV_{com}/dt = 20 \text{ V}/\mu\text{s}$ ; (snubberless condition); gate open circuit		15	-	-	A/ms

## 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1		
2	T2	main terminal 2		
3	G	gate		
mb	n.c.	mounting base; isolated	 TO-220AB (SOT78D)	 sym051

## 6. Ordering information

Table 3. Ordering information

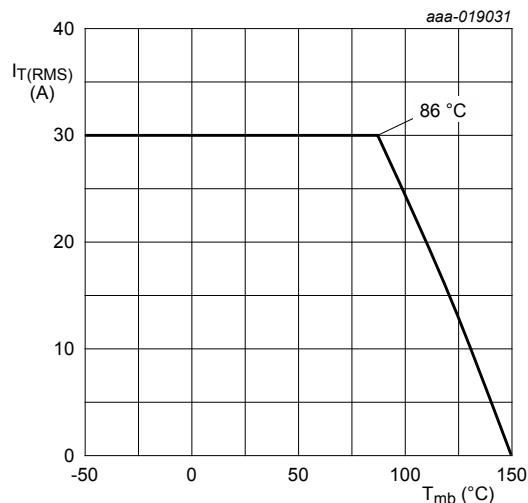
Type number	Package		
	Name	Description	Version
BTA330Y-800BT	TO-220AB	plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220	SOT78D

## 7. Limiting values

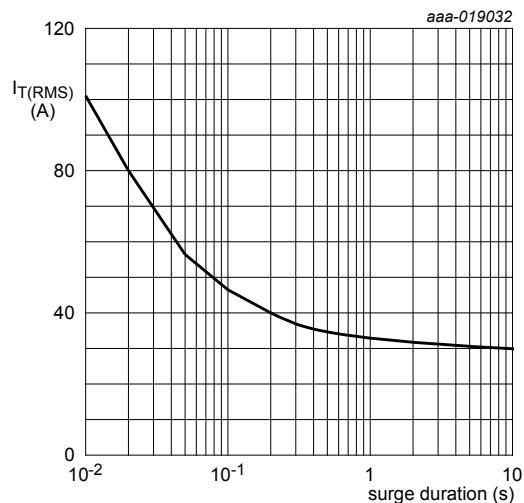
**Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage			-	800	V
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_{mb} \leq 86^\circ\text{C}$ ; <a href="#">Fig. 1</a> ; <a href="#">Fig. 2</a> ; <a href="#">Fig. 3</a>		-	30	A
$I_{TSM}$	non-repetitive peak on-state current	full sine wave; $T_{j(\text{init})} = 25^\circ\text{C}$ ; $t_p = 20\text{ ms}$ ; <a href="#">Fig. 4</a> ; <a href="#">Fig. 5</a>		-	270	A
		full sine wave; $T_{j(\text{init})} = 25^\circ\text{C}$ ; $t_p = 16.7\text{ ms}$		-	297	A
$I^2t$	$I^2t$ for fusing	$t_p = 10\text{ ms}$ ; sine-wave pulse		-	364.5	$\text{A}^2\text{s}$
$dI_T/dt$	rate of rise of on-state current	$I_G = 70\text{ mA}$		-	100	$\text{A}/\mu\text{s}$
$I_{GM}$	peak gate current			-	2	A
$P_{GM}$	peak gate power			-	5	W
$P_{G(AV)}$	average gate power	over any 20 ms period		-	0.5	W
$T_{stg}$	storage temperature			-40	150	$^\circ\text{C}$
$T_j$	junction temperature			-	150	$^\circ\text{C}$



**Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values**



**Fig. 2. RMS on-state current as a function of surge duration; maximum values**

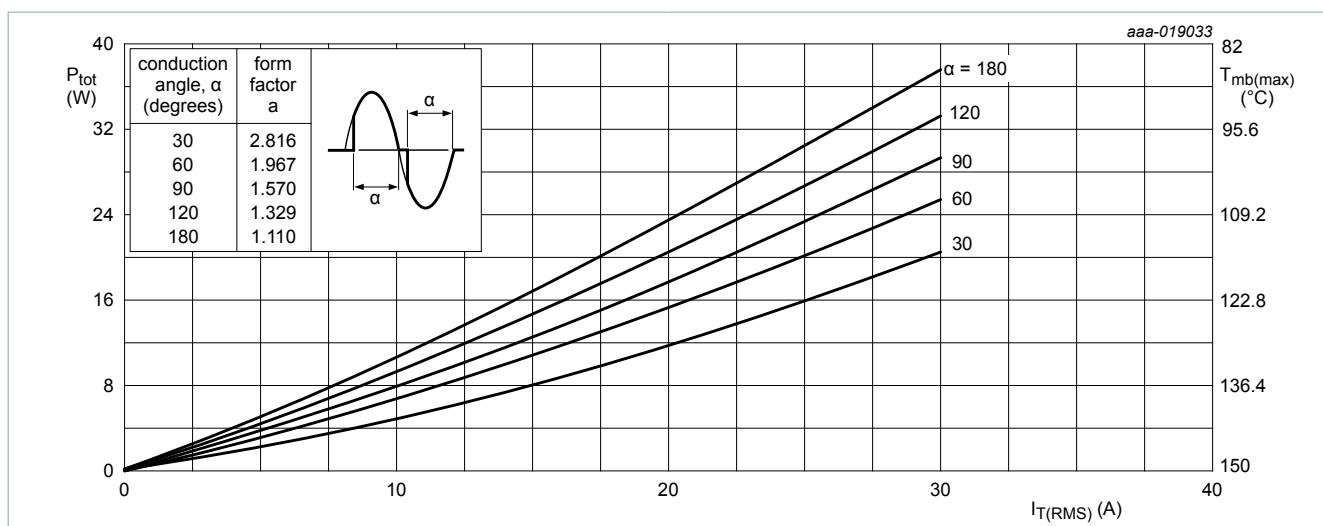


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

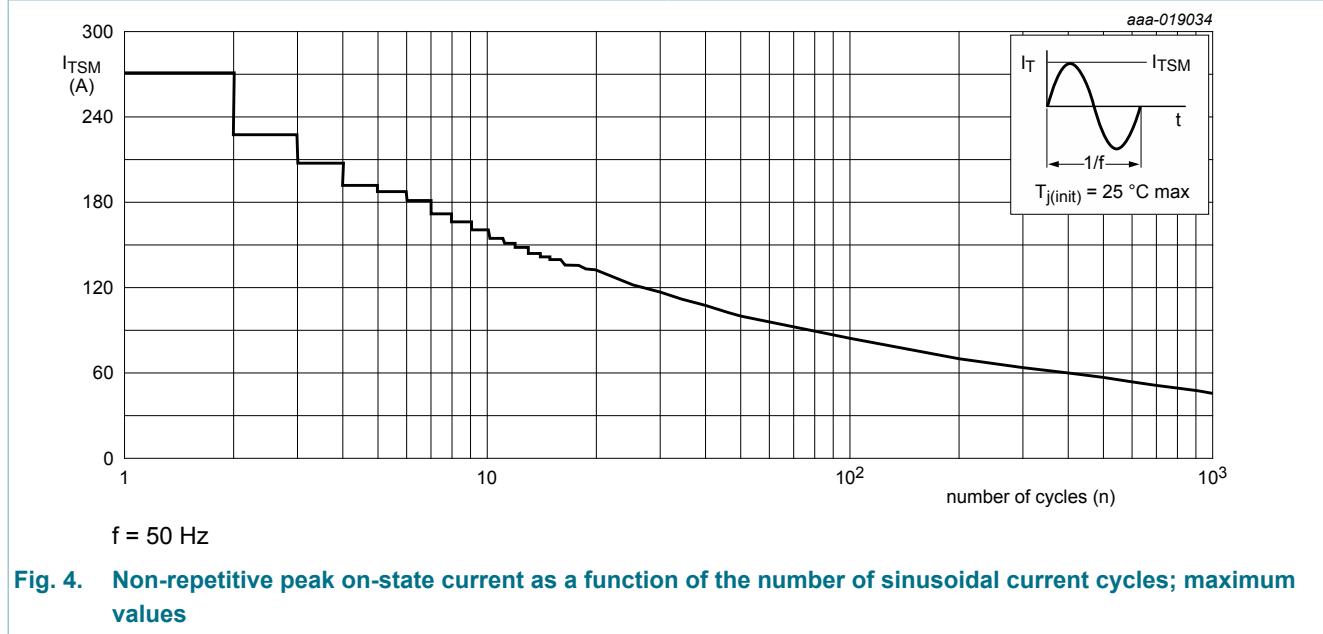
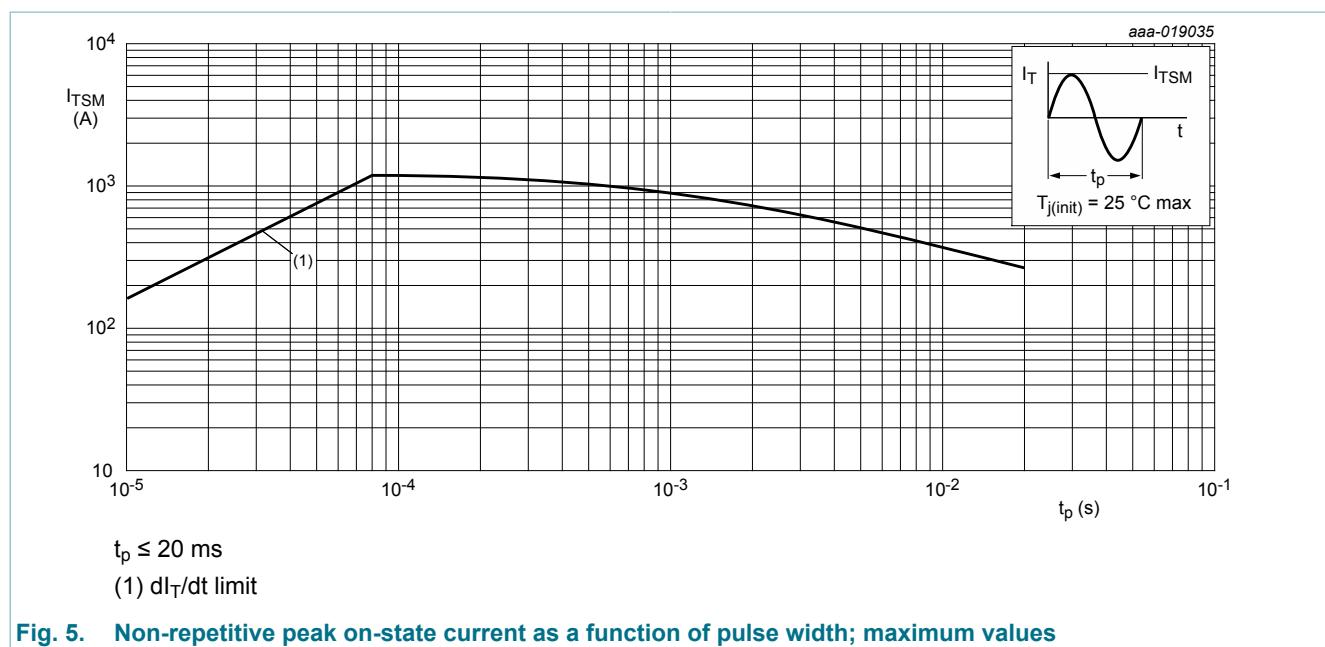


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



## 8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	full cycle; <a href="#">Fig. 6</a>		-	-	1.7	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient free air	in free air		-	60	-	K/W

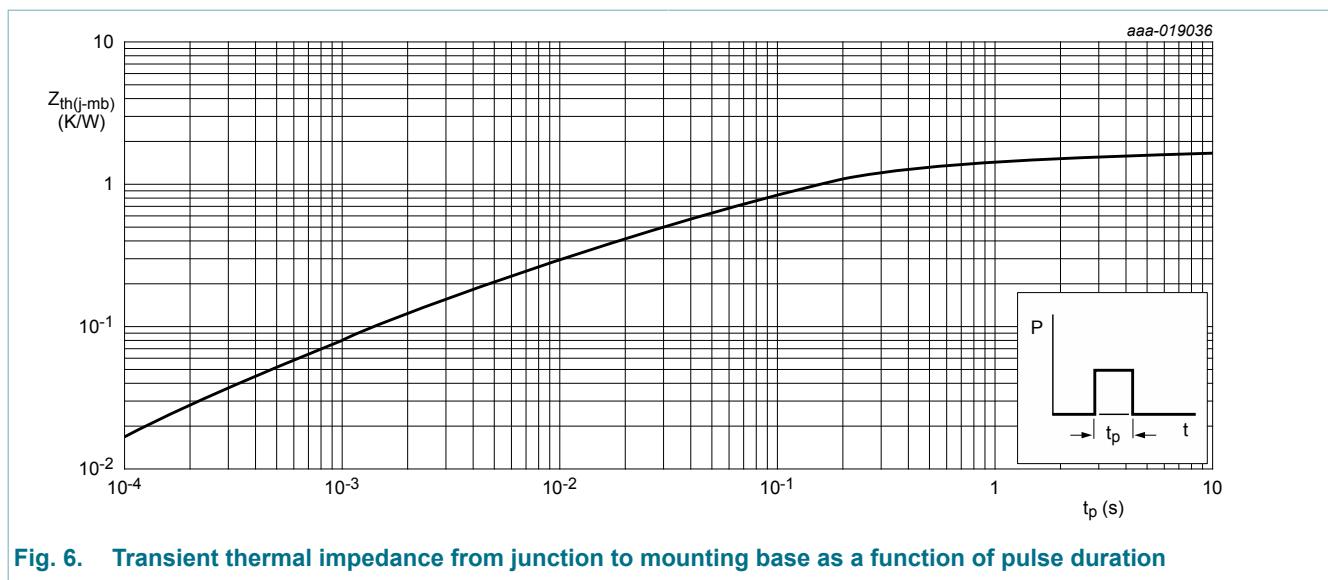


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

## 9. Isolation characteristics

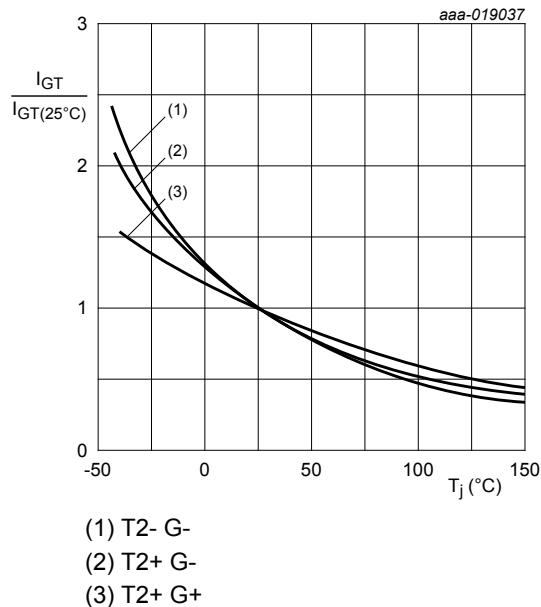
Table 6. Isolation characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$V_{isol(RMS)}$	RMS isolation voltage	from all terminals to external heatsink; sinusoidal waveform; clean and dust free; $50 \text{ Hz} \leq f \leq 60 \text{ Hz}$ ; $\text{RH} \leq 65 \%$ ; $T_{mb} = 25^\circ\text{C}$		-	-	2500	V
$C_{isol}$	isolation capacitance	from main terminal 2 to external heatsink; $f = 1 \text{ MHz}$ ; $T_{mb} = 25^\circ\text{C}$		-	10	-	pF

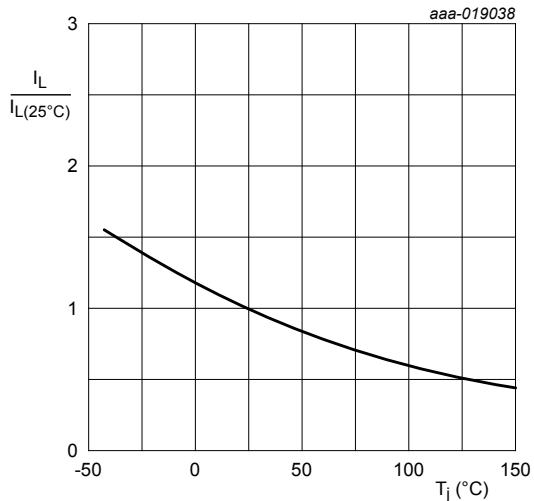
## 10. Characteristics

**Table 7. Characteristics**

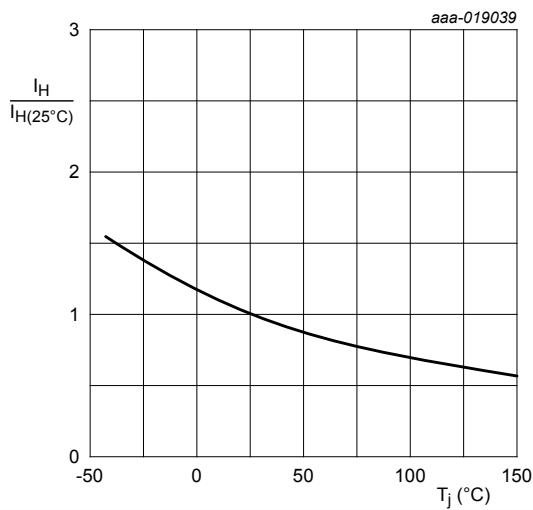
Symbol	Parameter	Conditions		Min	Typ	Max	Unit
<b>Static characteristics</b>							
I <sub>GT</sub>	gate trigger current	V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2+ G+; T <sub>j</sub> = 25 °C; <a href="#">Fig. 7</a>		-	-	50	mA
		V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2+ G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 7</a>		-	-	50	mA
		V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2- G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 7</a>		-	-	50	mA
I <sub>L</sub>	latching current	V <sub>D</sub> = 12 V; I <sub>G</sub> = 0.1 A; T2+ G+; T <sub>j</sub> = 25 °C; <a href="#">Fig. 8</a>		-	-	80	mA
		V <sub>D</sub> = 12 V; I <sub>G</sub> = 0.1 A; T2+ G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 8</a>		-	-	100	mA
		V <sub>D</sub> = 12 V; I <sub>G</sub> = 0.1 A; T2- G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 8</a>		-	-	80	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <a href="#">Fig. 9</a>		-	-	75	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 42 A; T <sub>j</sub> = 25 °C; <a href="#">Fig. 10</a>		-	1.2	1.55	V
V <sub>GT</sub>	gate trigger voltage	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <a href="#">Fig. 11</a>		-	0.9	1.3	V
		V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; <a href="#">Fig. 11</a>		0.2	0.45	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C		-	-	10	µA
		V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C		-	0.4	2	mA
<b>Dynamic characteristics</b>							
dV <sub>D</sub> /dt	rate of rise of off-state voltage	V <sub>DM</sub> = 536 V; T <sub>j</sub> = 125 °C; (V <sub>DM</sub> = 67% of V <sub>DRM</sub> ); exponential waveform; gate open circuit		4000	-	-	V/µs
		V <sub>DM</sub> = 536 V; T <sub>j</sub> = 150 °C; (V <sub>DM</sub> = 67% of V <sub>DRM</sub> ); exponential waveform; gate open circuit		2000	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	V <sub>D</sub> = 400 V; T <sub>j</sub> = 125 °C; I <sub>T(RMS)</sub> = 30 A; dV <sub>com</sub> /dt = 20 V/µs; (snubberless condition); gate open circuit		20	-	-	A/ms
		V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; I <sub>T(RMS)</sub> = 30 A; dV <sub>com</sub> /dt = 20 V/µs; (snubberless condition); gate open circuit		15	-	-	A/ms



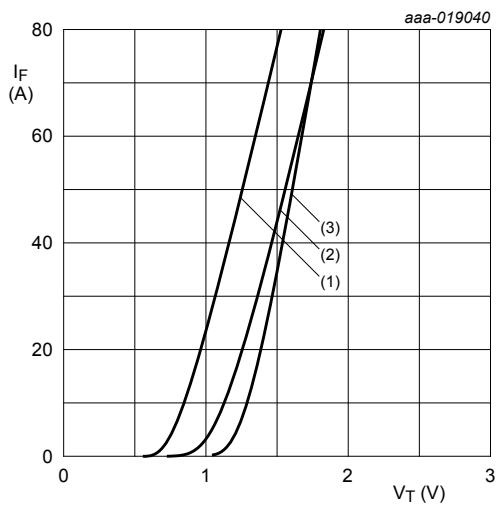
**Fig. 7. Normalized gate trigger current as a function of junction temperature**



**Fig. 8. Normalized latching current as a function of junction temperature**



**Fig. 9. Normalized holding current as a function of junction temperature**



**Fig. 10. On-state current as a function of on-state voltage**

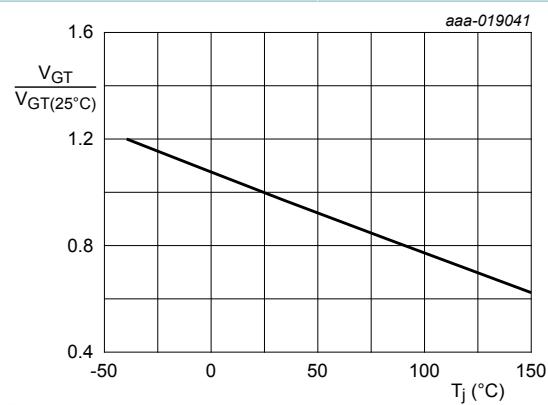
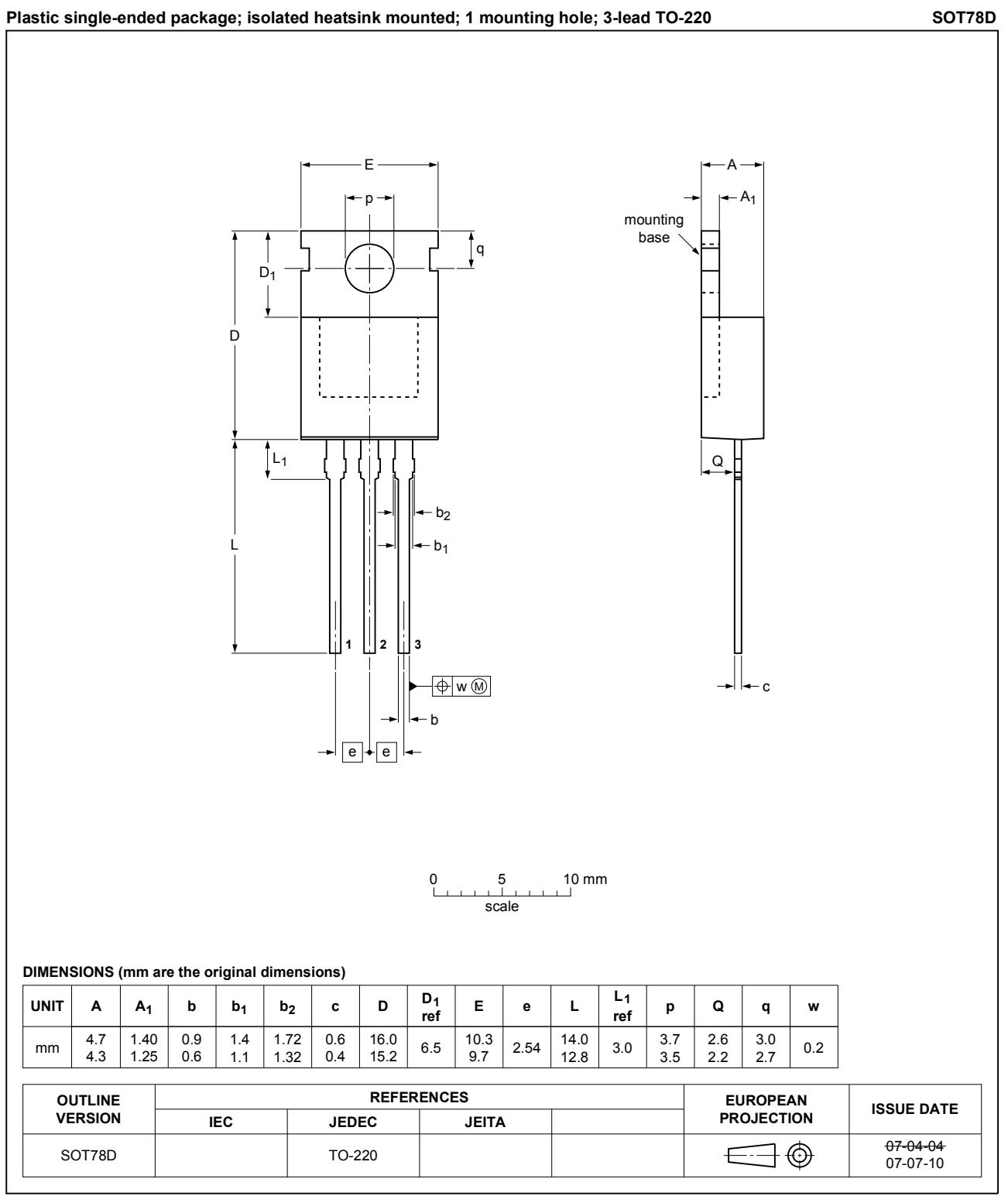


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

## 11. Package outline



## 12. Legal information

### 12.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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## 13. Contents

1	General description .....	1
2	Features and benefits .....	1
3	Applications .....	1
4	Quick reference data .....	1
5	Pinning information .....	3
6	Ordering information .....	3
7	Limiting values .....	4
8	Thermal characteristics .....	7
9	Isolation characteristics .....	7
10	Characteristics .....	8
11	Package outline .....	11
12	Legal information .....	12
12.1	Data sheet status .....	12
12.2	Definitions .....	12
12.3	Disclaimers .....	12
12.4	Trademarks .....	13

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